



Light Management for Optoelectronics

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Message from the Guest Editors

Light Management for Optoelectronics tries to call the attention of all the scientific community working on the improvement of optoelectronic device performance by means of optimized photon management. The scope could include:

- Interference based anti-reflection coatings (ARC)
- Anti-reflection effects of nano-rough interfaces and effective media
- Light scattering at randomly textured interfaces
- Light scattering at (quasi-)periodic geometries and corresponding production methods
- Resonant light trapping by means of photonic crystals
- Light coupling to waveguide modes in optoelectronic devices.
- Plasmonic nanostructures
- Intermediate reflector layers in multi-junction devices
- Light trapping structures and low temperature processes for light management
- External optical elements for light trapping
- Advanced optical modeling, especially with complex multi-junction configurations
- Characterization and assessment of light management in optoelectronic devices





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Message from the Editor-in-Chief

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